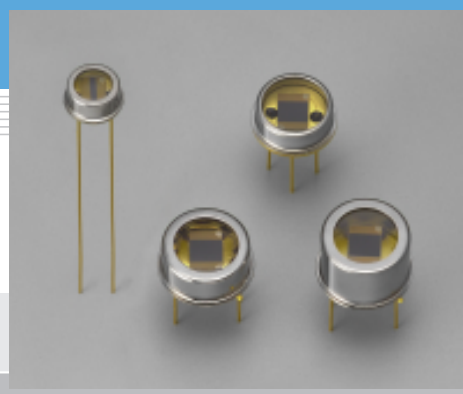


PbS photoconductive detector P394 series, P2532-01, P2682-01

Infrared detectors utilizing photoconductive effects



Features

- Room temperature operation
Makes PbS cells useful in a wide range of applications including radiation thermometers and flame monitors
- High sensitivity
- Large active area
- Low price
- Lower temperature detection limit: 100 °C
- Thermoelectrically cooled types available
Cooling a PbS cell increases sensitivity and improves S/N, so cooled types are widely used in precision photometry such as in analytical instruments.

Applications

- Radiation thermometers
- Flame monitors
- Water content analyzers
- Food ingredient analysis
- Spectrophotometers

Accessories (Optional)

- Heatsink for one-stage TE-cooled type A3179
- Heatsink for two-stage TE-cooled type A3179-01
- Temperature controller for TE-cooled type C1103-04
- Preamplifier for PbS/PbSe photoconductive detector C3757-02
- Power supply for amplifier C3871
- Infrared detector module with preamp Cooled type P4638

■ Specification / Absolute maximum ratings

Type No.	Dimensional outline/ Window material *1	Package	Cooling	Active area (mm)	Thermistor resistance (kΩ)	Absolute maximum ratings				
						Thermistor power dissipation (mW)	TE-cooler current dissipation (A)	Supply voltage (V)	Operating temperature Topr (°C)	Storage temperature Tstg (°C)
P394	①/K	TO-5	Non-cooled	1 × 5	-	-	-	100	-30 to +50	-55 to +50
P394-22	②/K	TO-8	Non-cooled	4 × 5	9	0.2	-			
P2532-01	③/S		One-stage TE-cooled				1.5			
P2682-01	④/S		Two-stage TE-cooled				1.0			

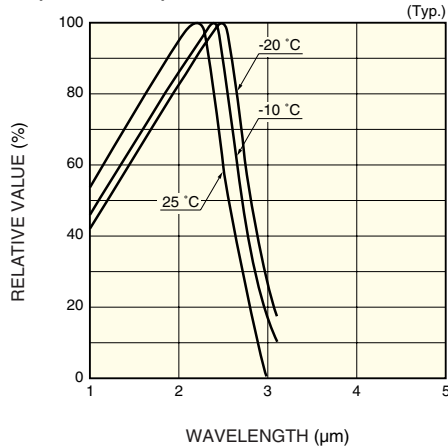
■ Electrical and optical characteristics (Typ. unless otherwise noted)

Type No.	Measurement condition	Peak sensitivity wavelength λ_p	Cut-off wavelength λ_c	Photo sensitivity *2 S $\lambda = \lambda_p$ $V_s = 15 \text{ V}$		D^* (500, 600, 1)		D^* (λ_p , 600, 1)	Rise time t_r 0 to 63 %	Dark resistance R_d
	Element temperature			Min.	Typ.	Min.	Typ.		Max.	
	(°C)	(μm)	(μm)	(V/W)	(V/W)	(cm·Hz ^{1/2} /W)	(cm·Hz ^{1/2} /W)	(cm·Hz ^{1/2} /W)	(μs)	(MΩ)
P394	25	2.2	2.9	4×10^4	1.3×10^5	5×10^8	1×10^9	1×10^{11}	200	0.1 to 1
P394-22				1.2×10^4	3×10^4	2×10^8	5×10^8	5×10^{10}		0.2 to 2
P2532-01	-10	2.4	3.1	3×10^4	8×10^4	5×10^8	1×10^9	1×10^{11}	600	0.5 to 10
P2682-01	-20	2.5	3.2	6×10^4	1.6×10^5	8×10^8	2×10^9	2×10^{11}		0.8 to 10

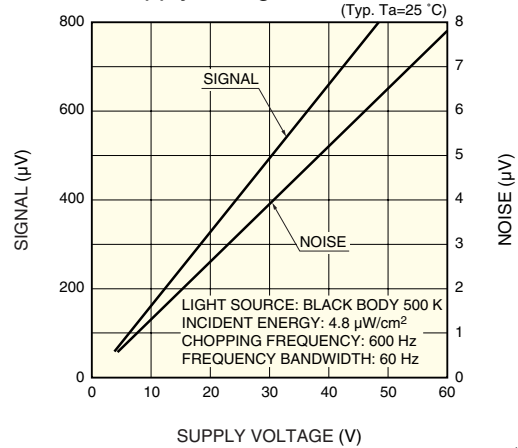
*1: Window material K: borosilicate glass, S: sapphire glass

*2: Chopping frequency: 600 Hz, load resistance: nearly equal to detector element dark resistance

Spectral response

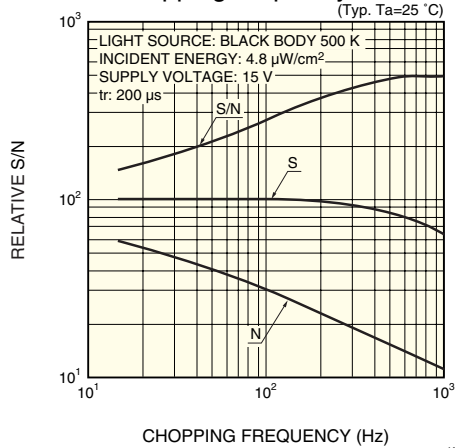


S/N vs. supply voltage



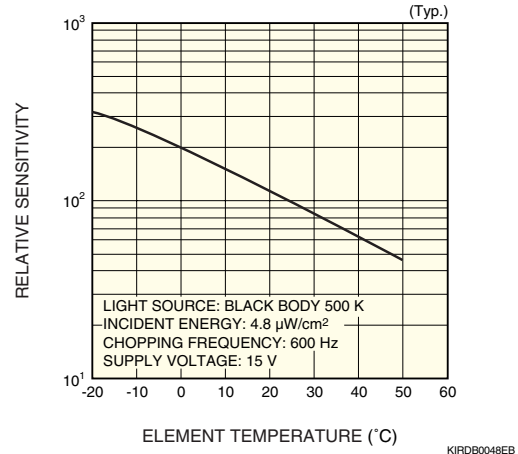
If voltage of higher than 60 V is applied, the noise increases exponentially, degrading the S/N. The device should be operated at 60 V or less.

S/N vs. chopping frequency



Increasing the chopping frequency reduces the $1/f$ noise and results in an S/N improvement. The S/N can also be improved by narrowing the noise bandwidth using a lock-in amplifier.

Photo sensitivity temperature characteristic



Cooling the device enhances its sensitivity, but the sensitivity also depends on the load resistance in the circuit.

Dark resistance, rise time temperature characteristics

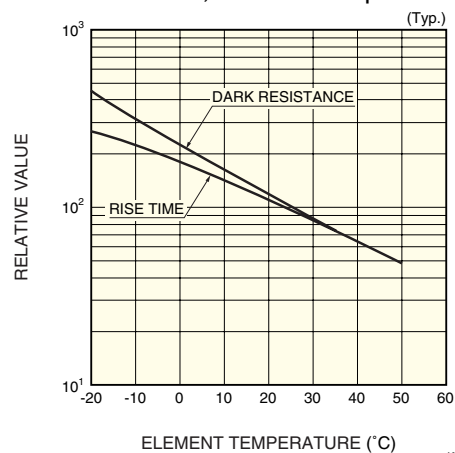
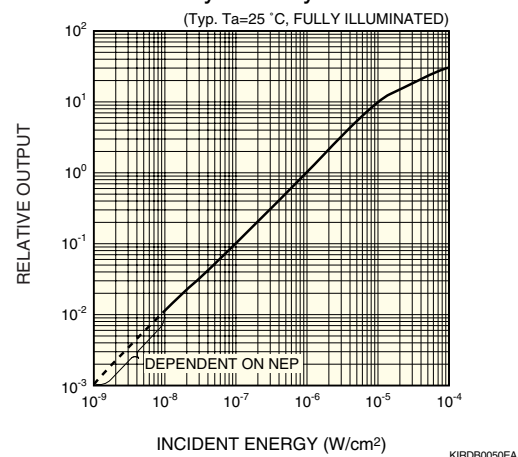
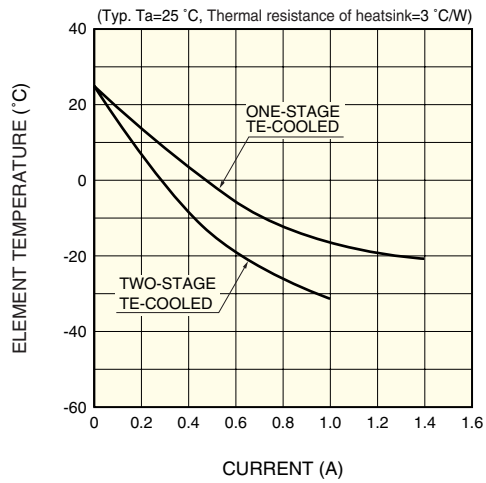


Photo sensitivity linearity

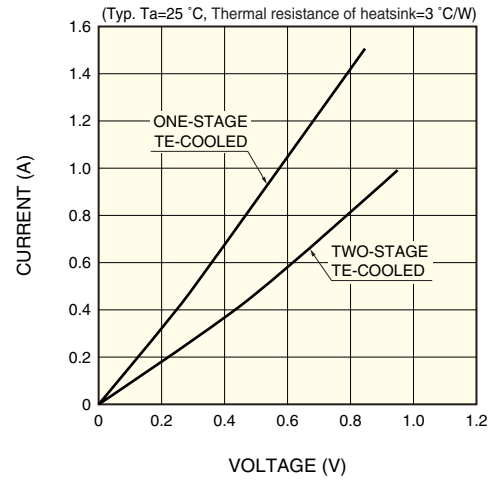


By making the incident light spot smaller than the active area, the upper limit of the linearity becomes lower.

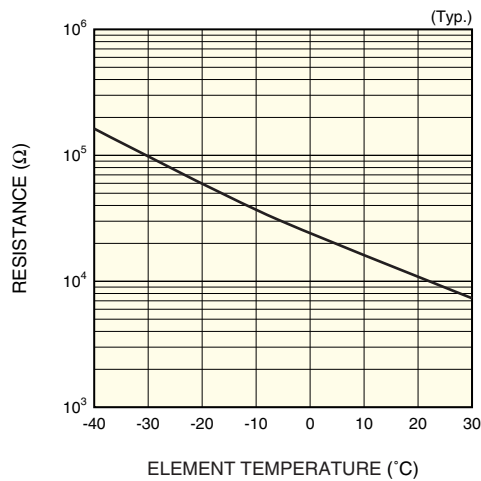
■ Cooling characteristics of TE-cooler



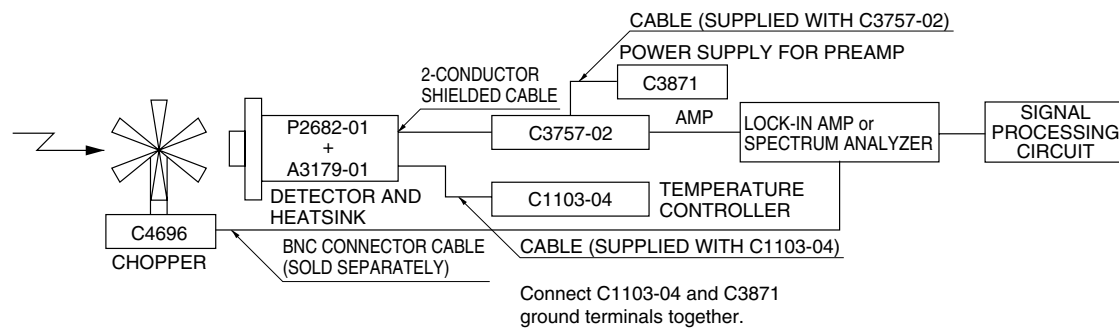
■ Current vs. voltage characteristics of TE-cooler



■ Thermistor temperature characteristic

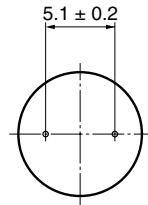
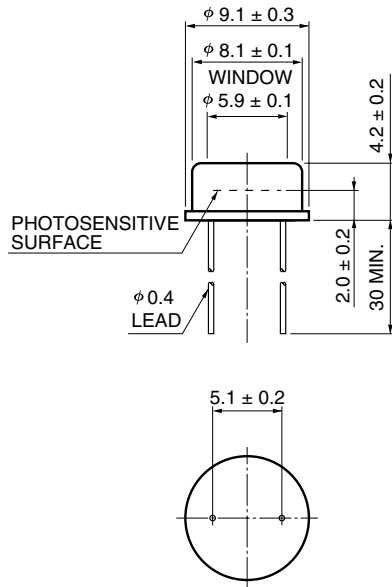


■ Connection example (P2682-01)



■ Dimensional outlines (unit: mm)

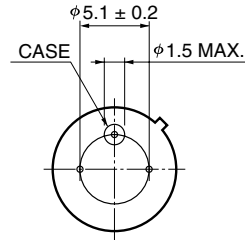
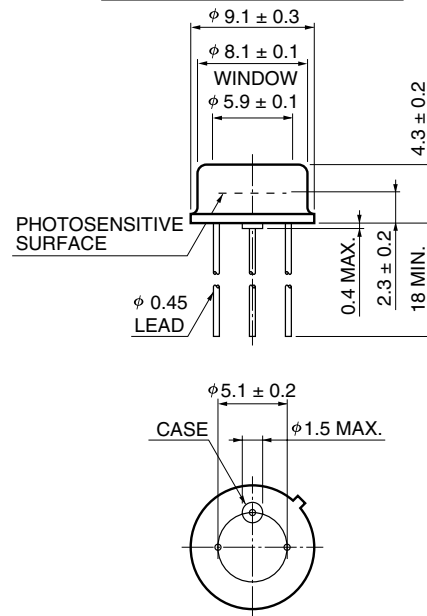
① P394



Note) Package dimension will be changed as shown at right from January 2003.

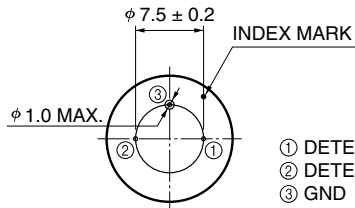
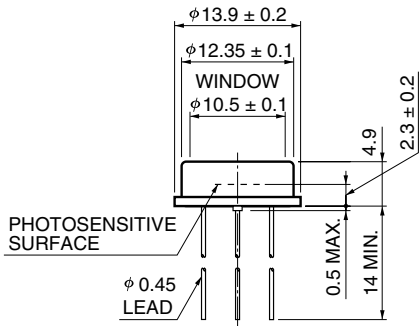
KIRDA0055EB

From January 2003



KIRDA0166EA

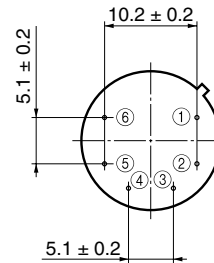
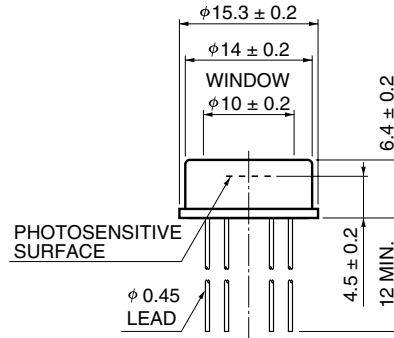
② P394-22



- ① DETECTOR
- ② DETECTOR
- ③ GND

KIRDA0115EA

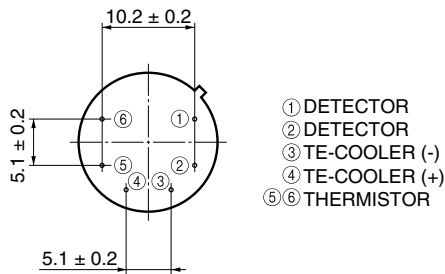
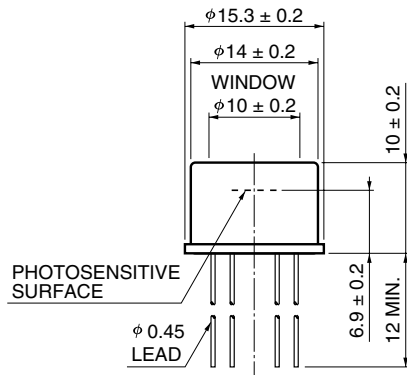
③ P2532-01



- ① DETECTOR
- ② DETECTOR
- ③ TE-COOLER (-)
- ④ TE-COOLER (+)
- ⑤ ⑥ THERMISTOR

KIRDA0116EA

④ P2682-01



KIRDA0117EA

HAMAMATSU

HAMAMATSU PHOTONICS K.K., Solid State Division

1126-1 Ichino-cho, Hamamatsu City, 435-8558 Japan, Telephone: (81) 053-434-3311, Fax: (81) 053-434-5184, <http://www.hamamatsu.com>

U.S.A.: Hamamatsu Corporation, 360 Foothill Road, P.O.Box 6910, Bridgewater, N.J. 08807-0910, U.S.A., Telephone: (1) 908-231-0960, Fax: (1) 908-231-1218

Germany: Hamamatsu Photonics Deutschland GmbH: Arzbergerstr. 10, D-82211 Herrsching am Ammersee, Germany, Telephone: (49) 08152-3750, Fax: (49) 08152-2658

France: Hamamatsu Photonics France S.A.R.L.: 8, Rue du Saule Trappu, Parc du Moulin de Massy, 91882 Massy Cedex, France, Telephone: 33-(1) 69 53 71 00, Fax: 33-(1) 69 53 71 10

United Kingdom: Hamamatsu Photonics UK Limited: 2 Howard Court, 10 Tewin Road, Welwyn Garden City, Hertfordshire AL7 1BW, United Kingdom, Telephone: (44) 1707-294888, Fax: (44) 1707-325777

North Europe: Hamamatsu Photonics Norden AB: Smidesvägen 12, SE-171 41 Solna, Sweden, Telephone: (46) 8-509-031-00, Fax: (46) 8-509-031-01

Italy: Hamamatsu Photonics Italia S.R.L.: Strada della Moia, 1/E, 20020 Arese, (Milano), Italy, Telephone: (39) 02-935-81-733, Fax: (39) 02-935-81-741

Information furnished by HAMAMATSU is believed to be reliable. However, no responsibility is assumed for possible inaccuracies or omissions. Specifications are subject to change without notice. No patent rights are granted to any of the circuits described herein. ©2003 Hamamatsu Photonics K.K.